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TECHNICAL REPORT

INTERNATIONAL SPECIAL COMMITTEE ON RADIO INTERFERENCE

Specification for radio disturbance and immunity measuring apparatus and methods –
Part 4-1: Uncertainties, statistics and limit modelling – Uncertainties in standardized EMC tests

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FOREWORD

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CISPR 16-4-1, which is a technical report, has been prepared by CISPR subcommittee A: Radio-interference measurements and statistical methods, of IEC technical committee CISPR: International special committee on radio interference.

This second edition of CISPR 16-4-1 cancels and replaces the first edition published in 2003, and its Amendments 1 (2004) and 2 (2007). It constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition. The provisions available for application of uncertainties in the determination of the

compliance criterion are explained more generally and a procedure is added for re-testing an approved EUT by another test house.

The text of this technical report is based on the following documents:

Enquiry draft	Report on voting
CISPR/A/818/DTR	CISPR/A/831/RVC

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts of the CISPR 16 series can be found, under the general title *Specification for radio disturbance and immunity measuring apparatus and methods*, on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the maintenance result date indicated on the IEC web site under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

A bilingual version of this publication may be issued at a later date.

INTRODUCTION

The result of the application of basic considerations (Clauses 4 and 5) in this part to existing or new CISPR standards will lead to proposals to improve and harmonise the uncertainty aspects of those CISPR standards. Such proposals will also be published as reports within this part and will give the background and rationale for improvement of certain CISPR standards. Clause 6 is an example of such a report.

The structure of clauses related to the CISPR standards compliance uncertainty work is depicted in Table 1. Clause 4 deals with the basic considerations of standards compliance uncertainties in emission measurements. Clauses 6, 7 and 8 contain uncertainty considerations related to voltage, absorbing clamp and radiated emission measurements, respectively.

Uncertainty work will also be considered for immunity compliance tests in the future. Clauses 5, 9 and 10 are reserved for this material. SCU (see 3.1.16) considerations of immunity tests differ from the emission SCU considerations in particular points. For instance, in an immunity test, the measurand is often a functional attribute of the EUT and not a specific quantity. This may cause additional specific SCU considerations. Priority has been given to the uncertainty evaluations for emission measurements at this stage of the work.

Table 1 – Structure of clauses related to the subject of standards compliance uncertainty

STANDARDS COMPLIANCE UNCERTAINTY			
Clause 1, 2, and 3: General			
EMISSION		**IMMUNITY**	
Clause 4	Basic considerations	Clause 5	Basic considerations
Clause 6	Voltage measurements	Clause 9	Conducted immunity tests
Clause 7	Absorbing clamp measurements	Clause 10	Radiated immunity tests
Clause 8	Radiated emission measurements		

SPECIFICATION FOR RADIO DISTURBANCE AND IMMUNITY MEASURING APPARATUS AND METHODS –

Part 4-1: Uncertainties, statistics and limit modelling – Uncertainties in standardized EMC tests

1 Scope

This part of CISPR 16-4 gives guidance on the treatment of uncertainties to those who are involved in the development or modification of CISPR electromagnetic compatibility (EMC) standards. In addition, this part provides useful background information for those who apply the standards and the uncertainty aspects in practice.

The objectives of this part are to:

a) identify the parameters or sources governing the uncertainty associated with the statement that a given product complies with the requirement specified in a CISPR recommendation. This uncertainty will be called “standards compliance uncertainty” (SCU, see 3.1.16);

b) give guidance on the estimation of the magnitude of the standards compliance uncertainty;

c) give guidance for the implementation of the standards compliance uncertainty into the compliance criterion of a CISPR standardised compliance test.

As such, this part can be considered as a handbook that can be used by standards writers to incorporate and harmonise uncertainty considerations in existing and future CISPR standards. This part also gives guidance to regulatory authorities, accreditation bodies and test engineers to judge the performance quality of an EMC test-laboratory carrying out CISPR standardised compliance tests. The uncertainty considerations given in this part can also be used as guidance when comparing test results (and their uncertainties) obtained by using different alternative test methods.

The uncertainty of a compliance test also relates to the probability of occurrence of an electromagnetic interference (EMI) problem in practice. This aspect is recognized and introduced briefly in this part. However, the problem of relating uncertainties of a compliance test to the occurrence of EMI in practice is not considered within the scope of this part.

The scope of this part is limited to all the relevant uncertainty considerations of a standardized EMC compliance test.

2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60050-161:1990, *International Electrotechnical Vocabulary (IEV) – Chapter 161: Electromagnetic Compatibility*

IEC 60050-300:2001, *International Electrotechnical Vocabulary (IEV) – Electrical and electronic measurements and measuring instruments – Part 311: General terms relating to measurements – Part 312: General terms relating to electrical measurements – Part 313: Types of electrical measuring instruments – Part 314: Specific terms according to the type of instrument*

IEC 60359:2001, *Electrical and electronic measurement equipment – Expression of performance*

CISPR 16-1-2:2003, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 1-2: Radio disturbance and immunity measuring apparatus – Conducted disturbances*

CISPR 16-1-3:2004, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 1-3: Radio disturbance and immunity measuring apparatus – Ancillary equipment – Disturbance power*

CISPR 16-1-4:2007, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 1-4: Radio disturbance and immunity measuring apparatus – Ancillary equipment – Radiated disturbances*

CISPR 16-1-5:2003, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 1-5: Radio disturbance and immunity measuring apparatus – Antenna calibration test sites for 30 MHz to 1 000 MHz*

CISPR 16-2-2:2003, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 2-2: Methods of measurement of disturbances and immunity – Measurement of disturbance power*
Amendment 1 (2004)
Amendment 2 (2005)

CISPR 16-2-3:2006, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 2-3: Methods of measurement of disturbances and immunity – Radiated disturbance measurements*

CISPR 16-4-2:2003, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 4-2: Uncertainties, statistics and limit modelling – Uncertainty in EMC measurements*

CISPR/TR 16-4-3:2004, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 4-3: Uncertainties, statistics and limit modelling – Statistical considerations in the determination of EMC compliance of mass-produced products*

CISPR 22:2008, *Information technology equipment – Radio disturbance characteristics – Limits and methods of measurement*

ISO/IEC 17025, *General requirements for the competence of testing and calibration laboratories*

ISO/IEC Guide 98-3:2008, *Uncertainty of measurement – Part 3: Guide to the expression of uncertainty in measurement* (GUM:1995)

ISO/IEC Guide 99:2007, *International vocabulary of metrology – Basic and general concepts and associated terms (VIM)*

3 Terms, definitions, and abbreviations

For the purposes of this document, the following terms, definitions and abbreviations apply.

NOTE 1 Wherever possible, existing terminology, from the normative standards of Clause 2 is used. Additional terms and definitions not included in those standards are listed below.

NOTE 2 Terms shown in **bold** are defined in this clause.

3.1 Terms and definitions

3.1.1

electromagnetic (EM) disturbance

any electromagnetic phenomenon which may degrade the performance of a device, equipment or system, or adversely affect living or inert matter

[IEV 161-01-05]

3.1.2

emission level

the level of a given electromagnetic disturbance emitted from a particular device, equipment or system measured in a specified way

[IEV 161-03-11, modified]

3.1.3

emission limit

the specified maximum emission level of a source of electromagnetic disturbance

NOTE In IEC this limit has been defined as "the maximum permissible emission level".

[IEV 161-03-12, modified]

3.1.4

influence quantity

quantity that is not the **measurand** but that affects the result of the measurement

[ISO/IEC Guide 98-3, B.2.10]

NOTE 1 In a standardised compliance test an influence quantity may be specified or non-specified. Specified influence quantities preferably include **tolerance** data.

NOTE 2 An example of a specified influence quantity is the measurement impedance of an artificial mains network. An example of a non-specified influence quantity is the internal impedance of an EM disturbance source.

3.1.5

interference probability

probability that a product complying with the EMC requirements will function satisfactorily (from an EMC point of view) in its normal use in an electromagnetic environment

3.1.6

intrinsic uncertainty of the measurand

minimum uncertainty that can be assigned in the description of a measured quantity. In theory, the intrinsic uncertainty of the measurand is obtained if the measurand is measured using a measurement system having a negligible **measurement instrumentation uncertainty**

NOTE 1 No quantity can be measured with continually lower uncertainty, inasmuch as any given quantity is defined or identified at a given level of detail. If one tries to measure a given quantity at an uncertainty lower than its own intrinsic uncertainty one is compelled to redefine it with higher detail, so that one is actually measuring another quantity. See also ISO/IEC Guide 98-3, D.1.1.

NOTE 2 The result of a measurement carried out with the intrinsic uncertainty of the measurand may be called the best measurement of the quantity in question.

[IEC 60359:2001, definition 3.1.11, modified]

3.1.7

intrinsic uncertainty of the measurement instrumentation

uncertainty of a measurement instrumentation when used under **reference conditions**. In theory, the intrinsic uncertainty of the measurement instrumentation is obtained if the **intrinsic uncertainty of the measurand** is negligible

NOTE Application of a reference EUT is a means to create reference conditions in order to obtain the intrinsic uncertainty of the measurement instrumentation (4.5.5).

[IEC 60359:2001, definition 3.2.10, modified]

3.1.8
level
value of a quantity, such as a power or a field quantity, measured and/or evaluated in a specified manner during a specified time interval

NOTE The level may be expressed in logarithmic units, for example in decibels with respect to a reference value.

[IEV 161-03-01, modified]

3.1.9
measurand
particular quantity subject to measurement

[IEV 311-01-03]

EXAMPLE Electric field, measured at a distance of 3 m, of a given sample.

NOTE The specification of a measurand may require statements about influence quantities (see ISO/IEC Guide 98-3, B.2.9).

3.1.10
measurement instrumentation uncertainty
MIU
parameter, associated with the result of a measurement that characterises the dispersion of the values that can reasonably be attributed to the **measurand**, induced by all relevant influence quantities that are related to the measurement instrumentation

[ISO/IEC Guide 99, 4.24, and IEC 60359:2001, 3.1.4, modified]

3.1.11
measuring chain
series of elements of a measuring instrument or system that constitutes the path of the measuring signal from input to the output

[IEV 311-03-07, modified]

3.1.12
(measurement) compatibility
property satisfied by all the results of measurement of the same **measurand**, characterized by an adequate overlap of their intervals

[IEV 311-01-14]

3.1.13
reference conditions
set of specified values and/or ranges of values of influence quantities under which the uncertainties, or limits of error, admissible for the measurement system are smallest

[IEV 311-06-02, modified]

3.1.14
reproducibility (of results of measurements)
closeness of the agreement between the results of successive measurements of the same **measurand** carried out under changed conditions as determined by one or more specified **influence quantities**